

ISO/IEC 10373-6

Cards and security devices for personal identification — Test methods —

Part 6: Contactless proximity objects

Cartes et dispositifs de sécurité pour l'identification personnelle — Méthodes d'essai —

Partie 6: Objets sans contact de proximité

**Fifth edition
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This fifth edition cancels and replaces the fourth edition (ISO/IEC 10373-6:2020), which has been technically revised. It also incorporates the Amendment ISO/IEC 10373-6:2020/Amd.2:2020.

The main changes are as follows:

- addition of explicit RFU reception test methods;
- modifications of the PICC transmission test methods;
- simplifications of the impedance matching networks; and
- corrections of the conformance test plan.

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